

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10570053	VISOZ ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
SUNG AHN	2611	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
375	346-350	12/16/2008	Sung Ahn
375	233	8/26/2009	Sung Ahn

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST Search (Please view search history list)	12/16/2008	Sung Ahn
IEEE Explorer (Searched with similar key words used in EAST search)	12/16/2008	Sung Ahn
Double Patent Search (Searched with inventors name in eDAN bib)	12/11/2008	Sung Ahn
EAST Search (Please view search history list)	8/22/2009	Sung Ahn
IEEE Explorer Search (Searched with similar key words used in EAST search)	8/22/2009	Sung Ahn
Search word help from the AU2611 Primary (Sam Ahn)	7/21/2009	Sung Ahn
Search word help from SPE (Mohammad Ghayour)	8/26/2009	Sung Ahn

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>